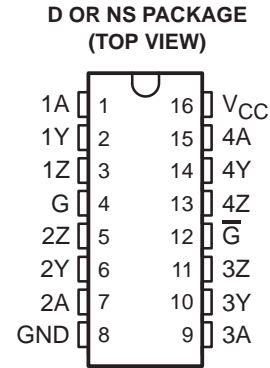


# AM26LV31 LOW-VOLTAGE HIGH-SPEED QUADRUPLE DIFFERENTIAL LINE DRIVER

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- Switching Rates up to 32 MHz
- Operates From a Single 3.3-V Supply
- Propagation Delay Time . . . 8 ns Typ
- Pulse Skew Time . . . 500 ps Typ
- High Output-Drive Current . . .  $\pm 30$  mA
- Controlled Rise and Fall Times . . . 3 ns Typ
- Differential Output Voltage With 100- $\Omega$  Load . . . 1.5 V Typ
- Ultra-Low Power Dissipation
  - dc, 0.3 mW Max
  - 32 MHz All Channels (No Load), 385 mW Typ
- Accepts 5-V Logic Inputs With a 3.3-V Supply
- Low-Voltage Pin-to-Pin Compatible Replacement for AM26C31, AM26LS31, MB571
- High Output Impedance in Power-Off Condition
- Driver Output Short-Protection Circuit
- Package Options Include Plastic Small-Outline (D, NS) Packages



The D package is available taped and reeled. The NS package is only available taped and reeled. Add the suffix R to device type (e.g., AM26LV31CDR).

## description

The AM26LV31 is a BiCMOS quadruple differential line driver with 3-state outputs. It is designed to be similar to TIA/EIA-422-B and ITU Recommendation V.11 drivers with reduced supply-voltage range.

The device is optimized for balanced-bus transmission at switching rates up to 32 MHz. The outputs have very high current capability for driving balanced lines such as twisted-pair transmission lines and provide a high impedance in the power-off condition. The enable function is common to all four drivers and offers the choice of active-high or active-low enable inputs. The AM26LV31 is designed using Texas Instruments (TI™) proprietary LinIMPACT-C60™ technology, facilitating ultra-low power consumption without sacrificing speed. This device offers optimum performance when used with the AM26LV32 quadruple line receivers.

The AM26LV31C is characterized for operation from 0°C to 70°C.

**FUNCTION TABLE**

| INPUT<br>A | ENABLES |           | OUTPUTS |   |
|------------|---------|-----------|---------|---|
|            | G       | $\bar{G}$ | Y       | Z |
| H          | H       | X         | H       | L |
| L          | H       | X         | L       | H |
| H          | X       | L         | H       | L |
| L          | X       | L         | L       | H |
| X          | L       | H         | Z       | Z |

H = high level, L = low level, X = irrelevant,  
Z = high impedance (off)



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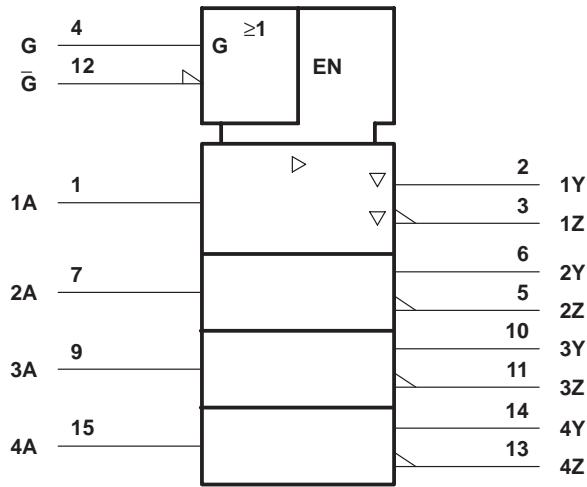
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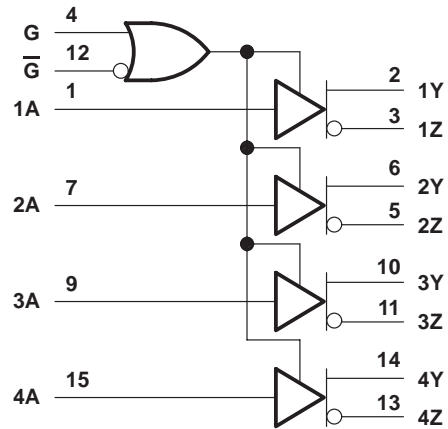
# AM26LV31 LOW-VOLTAGE HIGH-SPEED QUADRUPLE DIFFERENTIAL LINE DRIVER

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## logic symbol†

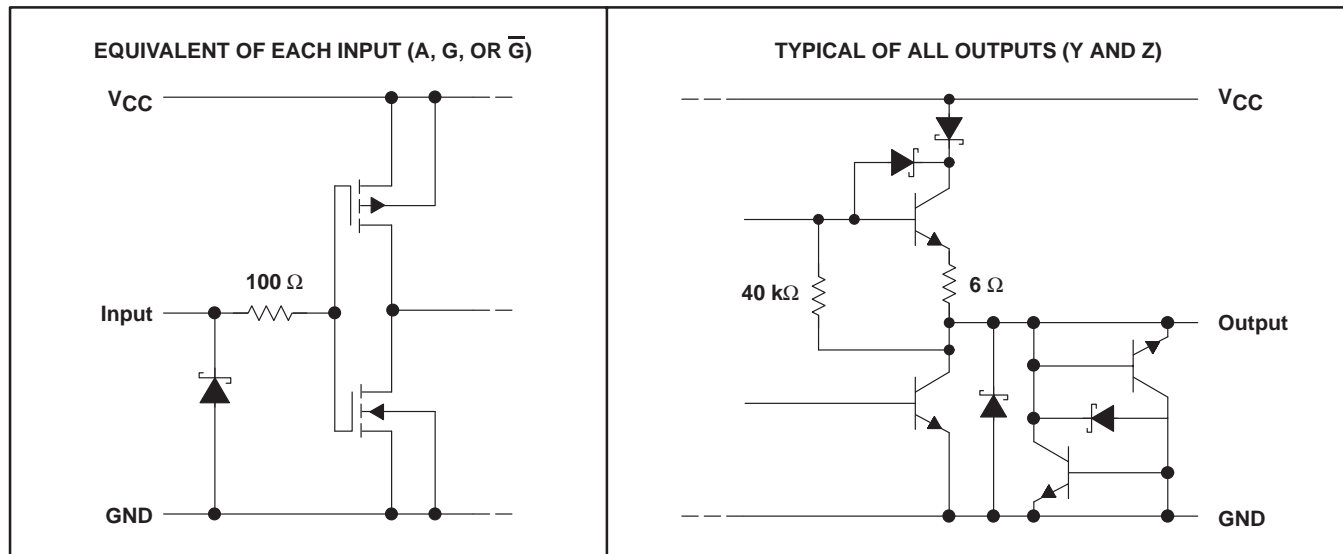


## logic diagram (positive logic)



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## schematic (each driver)



All resistor values are nominal.

**absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†**

|  |                |
|--|----------------|
| Supply voltage range, $V_{CC}$ (see Note 1) .....                      | –0.3 V to 6 V  |
| Input voltage range, $V_I$ .....                                       | –0.3 V to 6 V  |
| Output voltage range, $V_O$ .....                                      | –0.3 V to 6 V  |
| Package thermal impedance, $\theta_{JA}$ (see Note 2): D package ..... | 73°C/W         |
| NS package .....   | 64°C/W         |
| Storage temperature range, $T_{stg}$ .....                             | –65°C to 150°C |
| Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds .....     | 260°C          |

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. All voltage values are with respect to GND.  
 2. The package thermal impedance is calculated in accordance with JESD 51.

**recommended operating conditions**

|                                       | MIN | NOM | MAX | UNIT |
|---------------------------------------|-----|-----|-----|------|
| Supply voltage, $V_{CC}$              | 3   | 3.3 | 3.6 | V    |
| High-level input voltage, $V_{IH}$    | 2   |     |     | V    |
| Low-level input voltage, $V_{IL}$     |     |     | 0.8 | V    |
| High-level output current, $I_{OH}$   |     |     | –30 | mA   |
| Low-level output current, $I_{OL}$    |     |     | 30  | mA   |
| Operating free-air temperature, $T_A$ | 0   |     | 70  | °C   |

# AM26LV31

## LOW-VOLTAGE HIGH-SPEED

### QUADRUPLE DIFFERENTIAL LINE DRIVER

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electrical characteristics over recommended operating supply-voltage and free-air temperature ranges (unless otherwise noted)

| PARAMETER  | TEST CONDITIONS  | MIN  | TYP† | MAX  | UNIT |
|--|--|------|------|------|------|
| V <sub>IK</sub> Input clamp voltage                                    | I <sub>I</sub> = -18 mA  |      |      | -1.5 | V    |
| V <sub>OH</sub> High-level output voltage                              | V <sub>IH</sub> = 2 V, I <sub>OH</sub> = -12 mA                    | 1.85 | 2.3  |      | V    |
| V <sub>OL</sub> Low-level output voltage                               | V <sub>IL</sub> = 0.8 V, I <sub>OH</sub> = 12 mA                   |      | 0.8  | 1.05 | V    |
| V <sub>OD</sub>   Differential output voltage‡                         | R <sub>L</sub> = 100 Ω   | 0.95 | 1.5  |      | V    |
| V <sub>OC</sub> Common-mode output voltage                             |  | 1.3  | 1.55 | 1.8  | V    |
| Δ V <sub>OC</sub>   Change in magnitude of common-mode output voltage‡ |  |      |      | ±0.2 | V    |
| I <sub>O</sub> Output current with power off                           | V <sub>O</sub> = -0.25 V or 6 V, V <sub>CC</sub> = 0               |      |      | ±100 | μA   |
| I <sub>OZ</sub> Off-state (high-impedance state) output current        | V <sub>O</sub> = -0.25 V or 6 V, G = 0.8 V or $\overline{G}$ = 2 V |      |      | ±100 | μA   |
| I <sub>IH</sub> High-level input current                               | V <sub>CC</sub> = 0 or 3 V, V <sub>I</sub> = 5.5 V                 |      |      | 10   | μA   |
| I <sub>IL</sub> Low-level input current                                | V <sub>CC</sub> = 3.6 V, V <sub>I</sub> = 0                        |      |      | -10  | μA   |
| I <sub>OS</sub> Short-circuit output current                           | V <sub>CC</sub> = 3.6 V, V <sub>O</sub> = 0                        |      |      | -200 | mA   |
| I <sub>CC</sub> Supply current (all drivers)                           | V <sub>I</sub> = V <sub>CC</sub> or GND, No load                   |      |      | 100  | μA   |
| C <sub>pd</sub> Power dissipation capacitance (all drivers)§           | No load  |      | 160  |      | pF   |

† All typical values are at V<sub>CC</sub> = 3.3 V and T<sub>A</sub> = 25°C.

‡ Δ|V<sub>OD</sub>| and Δ|V<sub>OC</sub>| are the changes in magnitude of V<sub>OD</sub> and V<sub>OC</sub>, respectively, that occur when the input is changed from a high level to a low level.

§ C<sub>pd</sub> determines the no-load dynamic current consumption. I<sub>S</sub> = C<sub>pd</sub> × V<sub>CC</sub> × f + I<sub>CC</sub>

### switching characteristics, V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C

| PARAMETER  | TEST CONDITIONS         | MIN | TYP | MAX | UNIT |
|--|-------------------------|-----|-----|-----|------|
| t <sub>PLH</sub> Propagation delay time, low- to high-level output | See Figure 2            | 4   | 8   | 12  | ns   |
| t <sub>PHL</sub> Propagation delay time, high- to low-level output |                         | 4   | 8   | 12  | ns   |
| t <sub>t</sub> Transition time (t <sub>r</sub> or t <sub>f</sub> ) |                         |     | 3   |     | ns   |
| SR Slew rate, single-ended output voltage                          | See Note 3 and Figure 2 |     | 0.3 | 1   | V/ns |
| t <sub>PZH</sub> Output-enable time to high level                  | See Figure 3            |     | 10  | 20  | ns   |
| t <sub>PZL</sub> Output-enable time to low level                   | See Figure 4            |     | 10  | 20  | ns   |
| t <sub>PHZ</sub> Output-disable time from high level               | See Figure 3            |     | 10  | 20  | ns   |
| t <sub>PLZ</sub> Output-disable time from low level                | See Figure 4            |     | 10  | 20  | ns   |
| t <sub>sk(p)</sub> Pulse skew                                      | f = 32 MHz, See Note 4  |     | 0.5 | 1.5 | ns   |
| t <sub>sk(o)</sub> Skew limit                                      | f = 32 MHz, See Note 5  |     |     | 1.5 | ns   |
| t <sub>sk(lim)</sub> Skew limit (device to device)                 | f = 32 MHz, See Note 6  |     |     | 3   | ns   |

NOTES: 3. Slew rate is defined by:

$$SR = \frac{90\%(V_{OH} - V_{OL}) - 10\%(V_{OH} - V_{OL})}{t_r}, \text{ the differential slew rate of } V_{OD} \text{ is } 2 \times SR.$$

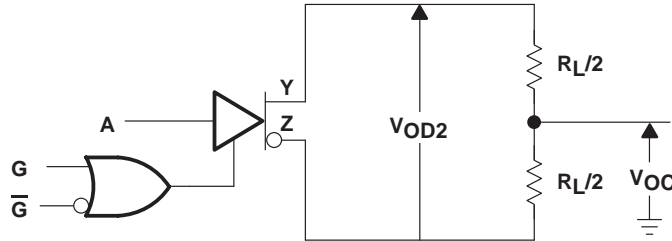
4. Pulse skew is defined as the |t<sub>PLH</sub> - t<sub>PHL</sub>| of each channel of the same device.

5. Skew limit is the difference between any two outputs of the same device switching in the same direction.

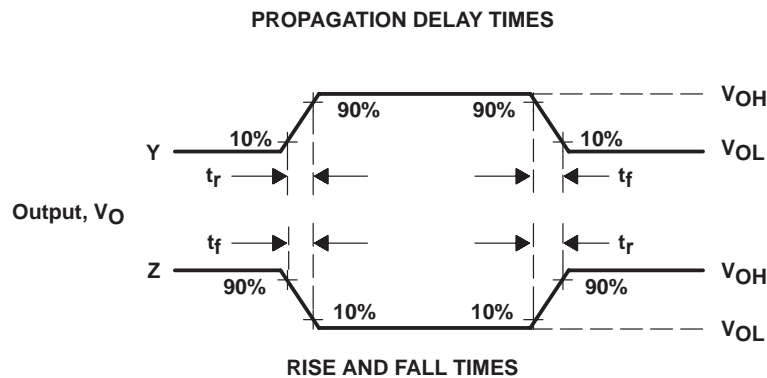
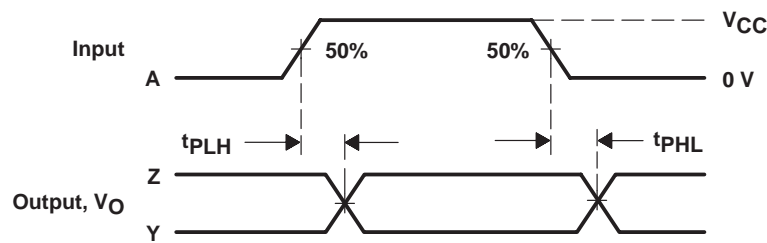
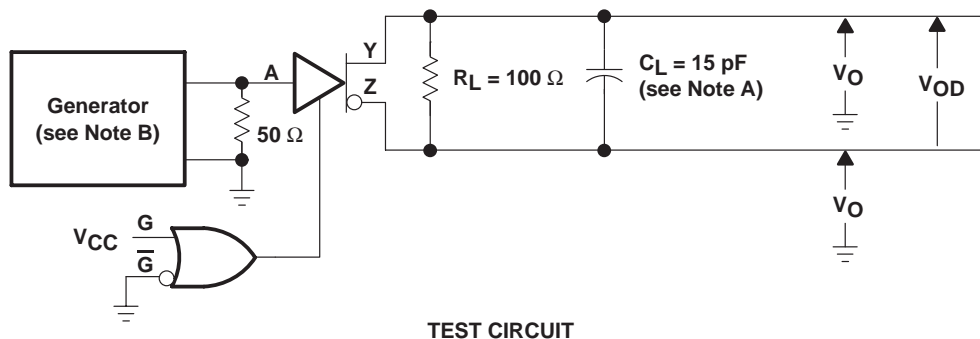
6. Skew limit (device to device) is the maximum difference in propagation delay times between any two channels of any two devices.



**PARAMETER MEASUREMENT INFORMATION**



**Figure 1. Differential and Common-Mode Output Voltages**



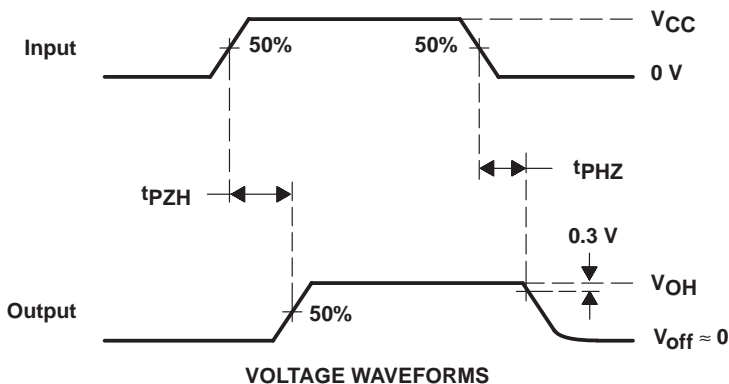
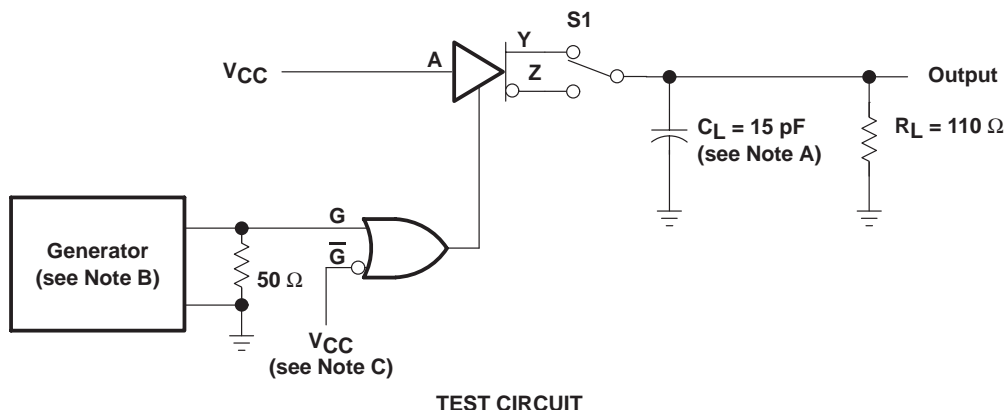
- NOTES: A.  $C_L$  includes probe and jig capacitance.  
 B. The input pulse is supplied by a generator having the following characteristics: PRR = 32 MHz,  $Z_O \approx 50 \Omega$ , 50% duty cycle,  $t_r$  and  $t_f \leq 2$  ns.

**Figure 2. Test Circuit and Voltage Waveforms,  $t_{PHL}$  and  $t_{PLH}$**

**AM26LV31**  
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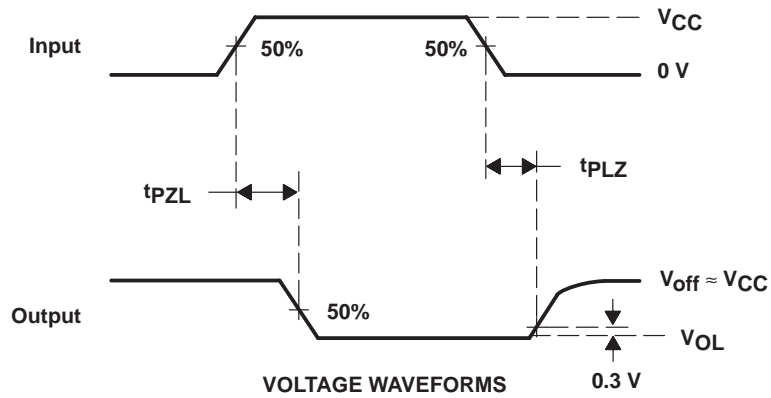
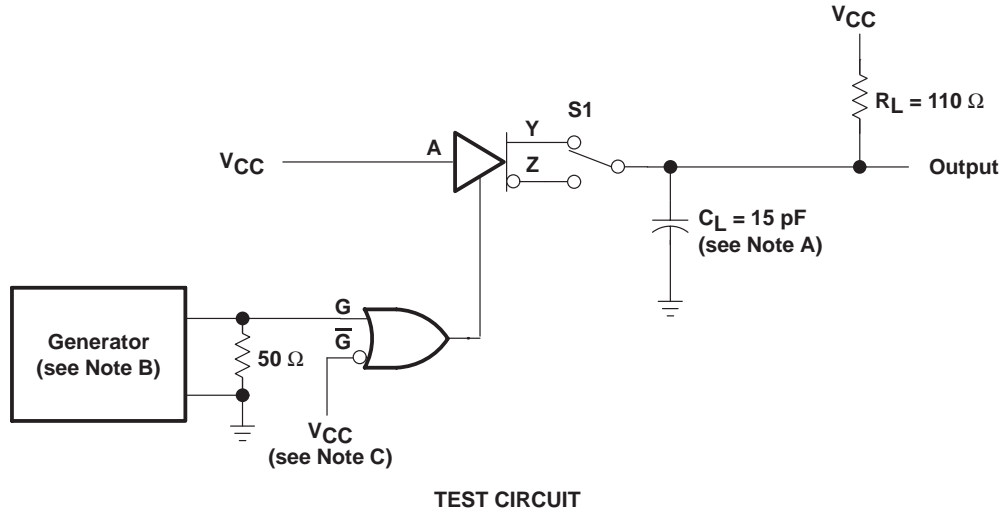
**PARAMETER MEASUREMENT INFORMATION**



- NOTES: A.  $C_L$  includes probe and jig capacitance.  
 B. The input pulse is supplied by a generator having the following characteristics: PRR = 1 MHz,  $Z_O = 50 \Omega$ , 50% duty cycle,  $t_r$  and  $t_f$  (10% to 90%)  $\leq 2$  ns.  
 C. To test the active-low enable  $\overline{G}$ , ground G and apply an inverted waveform to  $\overline{G}$ .

**Figure 3. Test Circuit and Voltage Waveforms,  $t_{pZH}$  and  $t_{pHZ}$**

**PARAMETER MEASUREMENT INFORMATION**



- NOTES: A.  $C_L$  includes probe and jig capacitance.  
 B. The input pulse is supplied by a generator having the following characteristics: PRR = 1 MHz,  $Z_O = 50 \Omega$ , 50% duty cycle,  $t_r$  and  $t_f$  (10% to 90%)  $\leq 2$  ns.  
 C. To test the active-low enable  $\overline{G}$ , ground G and apply an inverted waveform to  $\overline{G}$ .

**Figure 4. Test Circuit and Voltage Waveforms,  $t_{PZL}$  and  $t_{PLZ}$**

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